CONVEX Diagnostics Master Index
(C200 Series)

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Fourth Edition
December 1989

DN.

CONVEX Computer Corporation
Richardson, Texas USA

CONVEX Diagnostics Master Index
(C200 Series)
Order No. DHW-083
Fourth Edition

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Revision Sheet

CONVEX Diagnostics Master Index (C200 Series)

Edition	Document No.	Date	Description
Fourth	760-000430-000	December 1989	This edition reflects a new master index for updates to the three manuals in the kit.
Third	760-000033-200	May 1989	This edition reflects a change in the name of the manual to *CONVEX Diagnostics Master Index (C200 Series)*. Also, the master table of contents has been eliminated.
Second	760-000103-201	December 1988	Reflects the new table of contents and index for updates to the three manuals in the kit.
First	760-000103-200	June 1988	Describes the three manuals comprising the kit. Provides a master table of contents and index to all manuals.

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Chapter 1
Introduction

1.1 Overview

CONVEX Diagnostics Documentation (C200 Series) contains four separate volumes of diagnostic materials. This manual introduces the structure of the *CONVEX Diagnostics Documentation (C200 Series)*. It also includes a master index to all four volumes.

The *CONVEX Diagnostics Documentation (C200 Series)* is a reference tool for CONVEX personnel who use the diagnostic utilities, CONVEX customers who do their own maintenance, and the CONVEX diagnostics sustaining staff.

1.2 Scope

This documentation applies to all CONVEX C200 Series computers.

1.3 Documents Included

This documentation kit includes the following four CONVEX manuals in three seperate binders:

- Volume I (binder 1), *CONVEX Diagnostics Master Index (C200 Series)* — Use this manual to obtain a general overview of the diagnostics documentation as well as to find a master index to all documentation.
- Volume II (binder 1), *CONVEX Processor Diagnostics Manual (C200 Series)* — This document contains C200 Series diagnostic tests for the Service Processor Unit (SP2), Peripheral Interface Adapter (PIA), memory system, central processor unit utility board (CPX), uniprocessors, and multiprocessors.
- Volume III (binder 2), *CONVEX PBUS I/O System Diagnostics Manual* — This manual encompasses the operation and interpretation of the various Input/Output (I/O) system functional tests. These tests are system independent and will run on any CONVEX machine structure.
- Volume IV (binder 3), *CONVEX Diagnostic Utilities Manual (C200 Series)* — This document presents the diagnostic utilities for CONVEX C200 Series computers. The material describes the features of the Service Processor operating system and contains all diagnostic utilities for CONVEX C200 Series machines. This manual also contains a detailed explanation of the Diagnostics Shell (Dshell) and the Interactive Scan (Iscan) utilities and diagnostic file formats.

1.4 Dependencies

All volumes in this kit are designed to be used together to eliminate excessive repetition of technical data between manuals and to simplify the revision process. The master index is a comprehensive reference tool that makes using the kit (contained in three binders) easier.

1.5 Master Index

The master index, in chapter 2, makes finding a particular subject easier across all volumes. The index contains symbol and numeric sections as well as the usual alphabetical section. Alphabetization is in the following order:

1. symbols
2. numerals
3. letters from A to Z

Each section is preceded by a boldfaced title. Preceding each page number (which is the chapter number followed by a dash then the page number of that chapter) is a Roman numeral that indicates the volume referenced. A period is placed between the volume number and the chapter-page number. The following is an example index entry:

Command scripts, user created II.2-1, III.3-1, IV.2-1

The above entry indicates that references to user-created command scripts appear in volume II (*CONVEX Processor Diagnostics Manual (C200 Series)*) on page 1 of chapter 2, in volume III (*CONVEX PBUS I/O System Diagnostics Manual*) on page 1 of chapter 3, and in volume IV (*CONVEX Diagnostic Utilities Manual (C200 Series)*) on page 1 of chapter 2.

See cross-references guide the reader to preferred spellings and entry wording. *See also* cross-references point the way to related subjects.

1.6 Ordering Documentation

To order the most current version of this or any other CONVEX document, use the CONVEX product number. If the product number is not known, order by the exact title. In some situations, the most current version may not be desired. To receive a specific version of a manual, order the manual by its document, or part, number, which can be obtained by contacting the local CONVEX office or by calling the Technical Assistance Center.

The product number for this manual is DHW-083.
The document number for this manual is 760-000430-000.

1.6.1 Diagnostic Documentation Kit

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David Massey, Lead Writer
CONVEX Hardware Documentation

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Chapter 2
Master Index

2.1 Overview

This chapter contains the master index to the four volumes that comprise the *CONVEX Diagnostics Documentation* kit.

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